PCN Number: 201				L70407000 PC			N Date: Apr 28, 2017		
Title:	Qualification of process techr			as an additional wafe	er fab site o	option	for sel	ect devices in LBC5	
Customer	Contact:		PC	N Manager	D	ept:		Quality Services	
Proposed 1 st Ship Date:			Jul 28, 2017		Estimated Sample Availability:		nple	Date provided at sample request.	
Change Type:									
Assem	nbly Site			Assembly Process				mbly Materials	
Desig	า			Electrical Specifica			Mech	anical Specification	
Test S	lite			Packing/Shipping/	'Labeling		Test	Process	
🛛 Wafer	Bump Site		Wafer Bump Material				Wafe	r Bump Process	
🛛 Wafer	Fab Site			Wafer Fab Materia	als		Wafe	r Fab Process	
			Part number change						
	PCN Details								

Description of Change:

This change notification is to announce the qualification of CFAB as an additional wafer fab site option for the LBC5 devices listed in the product affected section of this document.

	Curre	nt Sites		Additional Sites				
Current Fab Site	Fab Process	Bump Site	Wafer Diameter	Additional Fab Site	Fab Process	Bump Site	Wafer Diameter	
DP1DM5	LBC5	DBUMP	200 mm	CFAB	LBC5	Clark-BP	200 mm	

The LBC5 process technology has been running successfully in production at CFAB since 2012.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative): None

Changes to product identification resulting from this PCN:

Current:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DP1DM5	DM5	USA	Dallas

New:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
CFAB	CU3	CHN	Chengdu

Sample product shipping label (not actual product label)

TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 20: MSL 2 /260C/1 YEAR MSL 2 /260C/1 YEAR MSL 1 /235C/UNLIM 03/29/04 OPT: 39 LBL: 5A (L)T0:1750	(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2 (P) (2D) REV: (V) 0033317 (20L) CS0: SHD (21L) CC0:USA (22L) AS0: MLA (23L) ACU: MYS

Product Affected:

DRV8313PWP	DRV8803PWPR	DRV8805PWP	DRV8844PWP
DRV8313PWPR	DRV8804PWP	DRV8805PWPR	DRV8844PWPR
DRV8803PWP	DRV8804PWPR		

Qualification Report

CFAB OFFLOAD FROM DMOS5 - Moobot (DRV8803PWPR) Approve Date 12-Nov-2015

Product Attributes

Die Attributes	Qual Device: C8803A0A	QBS Product Reference: DRV8803PWP	QBS Product Reference: DRV8804DW-P	QBS Process Reference: TA S5613APHD	QBS Package Reference: BUF11704AIPWPR	QBS Package Reference: TPA1517DWP	QBS Package Reference: TPS40057PWP	QBS Package Reference: TPS65161PWP
Assembly Site	TITL	TI TAIWAN	MLA (TIM)	TAI (TITL)	TAI	TAI	TAI	TAI
Package Family	HTSSOP	HTSSOP	SOIC - DW	HTQFP	TSSOP	SOIC	TSSOP	TSSOP
Wafer Fab Supplier	CFAB	DM5	DM5	CFAB	DMOS5	SFAB	DFAB	DFAB
Wafer Process	LBC5	LBC-5X	LBC5	LBC5	50HPA07	Bipolar	LBC4	LBC4x

- QBS: Qual By Similarity - Qual Device C8803A0A is qualified at LEVEL3-260CG

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: C8803A0A	QBS Product Reference: DRV8803PWP	QBS Product Reference: DRV8804DW-P	QBS Process Reference: TAS5613APHD	QBS Package Reference: BUF11704AIPWPR	QBS Package Reference: TPA1517DWP	QBS Package Reference: TPS40057PWP	QBS Package Reference: TPS65161PWP
AC	Autoclave 121C	96 Hours		-	-	3/231/0	1/77/0	3/231/0	1/77/0	1/77/0
ED	ElectricalCharacterization	Per Datasheet Parameters	Pass	-	Pass	Pass	-	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours		-		3/231/0	-	3/78/0	-	-
HBM	ESD - HBM	3000 V	-	-	1/3/0	-	-	-	-	-
CDM	ESD - CDM	1500 V	-	1/3/0	1/3/0	-	-	-	-	-
HTOL	Life Test, 125C	1000 Hours	-	-	-	-	-	3/120/0	-	-
HTOL	Life Test, 155C	240 Hours	-	-	-	3/231/0	-	-	-	-
HTSL	High Temp. StorageBake, 170C	420 Hours	-	-	-	3/230/0	1/77/0	3/231/0	1/77/0	1/77/0
LU	Latch-up	(per JESD78)	-	-	1/6/0	3/18/0	-	-	-	-
SBS	Ball Shear	Wires	-	-	-	-	1/76/0	-		-
TC	Temperature Cycle -65C/150C	500 Cycles	-	2/154/0	3/231/0	3/231/0	1/77/0	3/231/0	1/77/0	1/77/0
TS	Thermal Shock, -65/150C	500 Cycles	-	-	-	-	1/77/0	3/231/0	1/77/0	1/77/0
WBP	Bond Pull	Wires	-	-	-	-	1/76/0	3/228/0	-	-
WBS	Bond Shear econditioning was performed for Autoclave	Wires	-	-	-	-	-	3/228/0	-	-

The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours The following are equivalent Tem Cyclo epitons per LESU-7-55C/125C/100 Cycles and -55C/150C/150C/Cycles busity and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free (SMT) and Green

Qualification Report

CFAB OFFLOAD from DMOS5 (DRV8844PWPR) Approve Date 12-Nov-2015

Product Attributes

Die Attributes	Qual Device: C8844A1	QBS Product Reference: DRV8844PWP	QBS Process Reference: TAS5613APHD	QBS Package Reference: BUF11704AIPWPR	QBS Package Reference: TPA1517DWP	QBS Package Reference: TPS40057PWP	QBS Package Reference: TPS65161PWP
Assembly Site	TITL	TAI	TAI (TITL)	TAI	TAI	TAI	TAI
Package Family	HTSSOP	-	HTQFP	TSSOP	SOIC	TSSOP	TSSOP
Wafer Fab Supplier	CFAB	DM0S5	CFAB	DMOS5	SFAB	DFAB	DFAB
Wafer Process	LBC5	LBC5X	LBC5	50HPA07	Bipolar	LBC4	LBC4x

- QBS: Qual by Similarity
 - Qual Device C8844A1 is qualified at LEVEL3-260CG

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: C8844A1	QBS Product Reference: DRV8844PWP	QBS Process Reference: TA S5613APHD	QBS Package Reference: BUF11704AIPWPR	QBS Package Reference: TPA1517DWP	QBS Package Reference: TPS40057PWP	QBS Package Reference: TPS65161PWP
AC	Autoclave 121C	96 Hours	-	-	3/231/0	1/77/0	3/231/0	1/77/0	1/77/0
ED	ElectricalCharacterization	Per Datasheet Parameters	1/30/0	1/30/0	1/30/0	-	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	-	3/78/0	-	
HBM	ESD - HBM	3000 V	-	1/3/0	-	-	-	-	-
CDM	ESD - CDM	1500 V	-	1/3/0	-	-	-	-	-
HTOL	Life Test, 125C	1000 Hours	-	-	-	-	3/120/0	-	-
HTOL	Life Test, 155C	240 Hours	-	-	3/231/0	-	-	-	-
HTSL	High Temp. StorageBake, 170C	420 Hours	-	-	3/230/0	1/77/0	3/231/0	1/77/0	1/77/0
LU	Latch-up	(per JESD78)	-	2/12/0	3/18/0	-	-	-	-
SBS	Ball Shear	Wires	-	-	-	1/76/0	-	-	-
TC	Temperature Cycle, -65/150C	500 Cycles	-	1/77/0	3/231/0	1/77/0	3/231/0	1/77/0	1/77/0
TS	Thermal Shock, -65/150C	500 Cycles	-	-	-	1/77/0	3/231/0	1/77/0	1/77/0
WBP	Bond Pull	Wires	-	-	-	1/76/0	3/228/0	-	-
WBS	Bond Shear	Wires	-	-	-	-	3/228/0	-	-
	reconditioning was performed for Autocla		AST, Temperature Cycle	Thermal Shock, and HTSL, as ap	plicable	-	3/220/0	-	-

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours - The following are equivalent THSL options based on an activation energy of 0.7eV: 155C/1k Hours, and 170C/420 Hours - The following are equivalent Tem Cycloe options per LeSt047--85C/125C/700 Cycles and 456C/150C/5500 Cycles Grand/Punde Strute:

Green/Pb-free Status: Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com